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IEC 60747-1:2006+A1:2010, IDT

(ICS 31.080)

SINGAPORE STANDARD

Semiconductor devices

– Part 1: General

Singapore Standards Council

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This Singapore Standard was prepared by the Working Group on Semiconductor Devices set up by the Technical Committee on Electrical and Electronic Products under the purview of the Electrical and Electronic Standards Committee.

This standard is an identical adoption of IEC 60747-1:2006+A1:2010, “Semiconductor devices – Part 1: General”, published by the International Electrotechnical Commission.

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Semiconductor devices –
Part 1: General

Dispositifs à semiconducteurs –
Partie 1: Généralités

IEC 60747-1:2006-02+AMD1:2010-05 CSV(en-fr)

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INTERNATIONAL STANDARD

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Semiconductor devices –
Part 1: General

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES –

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IEC 60747-1 edition 2.1 contains the second edition (2006) [documents 47/1841/FDIS and 47/1848/RVD], its amendment 1 (2010) [documents 47/2015A/CDV and 47/2038A/RVC] and its corrigendum of September 2008.

A vertical line in the margin shows where the base publication has been modified by amendment 1. Additions and deletions are displayed in red, with deletions being struck through.

International Standard IEC 60747-1 has been prepared by IEC technical committee 47: Semiconductor devices.

The main changes with respect to the previous edition are listed below.

a) The terminology which is now given in the IEV (or which was in conflict with the IEV) has been omitted.
b) There has been a general revision of guidance on essential ratings and characteristics.
c) The distinction between general and reference methods of measurement has been removed.
d) A clause on product discontinuation notice has been added.

This bilingual version, published in 2009-11, corresponds to the English version.

The French version of this standard has not been voted upon.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all the parts in the IEC 60747 series, under the general title *Semiconductor devices*, can be found on the IEC website.

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SEMICONDUCTOR DEVICES –

Part 1: General

1 Scope

This part of IEC 60747 gives the general requirements applicable to the discrete semiconductor devices and integrated circuits covered by the other parts of IEC 60747 and IEC 60748 (see Annex A).

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050-521, *International Electrotechnical Vocabulary (IEV) – Part 521: Semiconductor devices and integrated circuits*

IEC 60050-702, *International Electrotechnical Vocabulary (IEV) – Part 702: Oscillations, signals and related devices*

IEC 60068 (all parts), *Environmental testing*

IEC 60191-2, *Mechanical standardization of semiconductor devices – Part 2: Dimensions*

IEC 60747 (all parts), *Semiconductor devices*

IEC 60748 (all parts), *Semiconductor devices – Integrated circuits*

IEC 60749-26, *Semiconductor devices – Mechanical and climatic test methods – Part 26: Electrostatic discharge (ESD) sensitivity testing – Human body model (HBM)*

IEC 61340 (all parts), *Electrostatics*

QC 001002 (all parts), *IEC Quality Assessment Systems for Electronic Components (IECQ) – Rules of procedure*

ISO 9000, *Quality management systems – Fundamentals and vocabulary*